# Chemical tuning as a new parameter to control HIOS thin-film growth

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## Growth control beyond substrate temperature and growth-rate



incorporation of local dipole moments electrostatic interactions (tunable strength)

changes in intermolecular

### Crystal phase purification

6P and the derivatives prefer an almost standing upright configuration. The crystal quality of all films is good (Bragg reflections up to the 6th order in the out-of-plane direction).

**6**P



6P-F4





DFG

We study the growth of 6P and its derivatives on ZnO (1010) as a model HIOS system. The beneficial optical properties of 6P, e.g. fluorescence, are not affected by the chemical tuning. The deposition of the molecules was performed by OMBD in UHV (~ $10^{-10}$  mbar) conditions.





of 6P.

Zinc Oxygen As on other substrates 6P grows in two phases on ZnO (1010). The phasecontent is temperature dependent. No indication for a second crystal-phase was found for any of the derivatives

Thus, chemical tuning of 6P through -F and -CN groups leads to a crystal-phase purification.

### Watching the growing thin-film

We use synchrotron radiation sources to study the temporal evolution of the intensity of the reflected X-ray beam (XRR) in situ and in real-time.





## Surface induced phases

6P-F4





#### Fluor-induced surface smoothing



The X-ray reflectivity data at fixed q points (e.g. at the Anti-Bragg point) exhibits growth oscillations.

Damping of oscillations is a measure for the surface roughening. By applying analytical models [1-4] we can extract the growth-mode and roughness evolution and compare with AFM data.

#### The exact molecular orientation, i.e. the tilt angle, is also chemically tuned. For 6P derivatives we find a gradual change of the (00I) Bragg reflections with increasing film thickness.

The reason for the peak shift is a surface induced structure that is different from the bulk.

Interlayer transport is correlated via the Ehrlich-Schwoebel barrier with molecular tilt angle [5].







#### Chemical tuning presents a promising new strategy to control organic thin-film growth.

We find a strong impact on the morphology and growth kinetics. By rational incorporation of different functional groups into the building block of well-known molecules a design of HIOS interfaces is possible.



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